

HIGH PURITY REGULATOR HPRSS4

PHOTOVOLTAIC • SEMICONDUCTOR

Facility Regulator



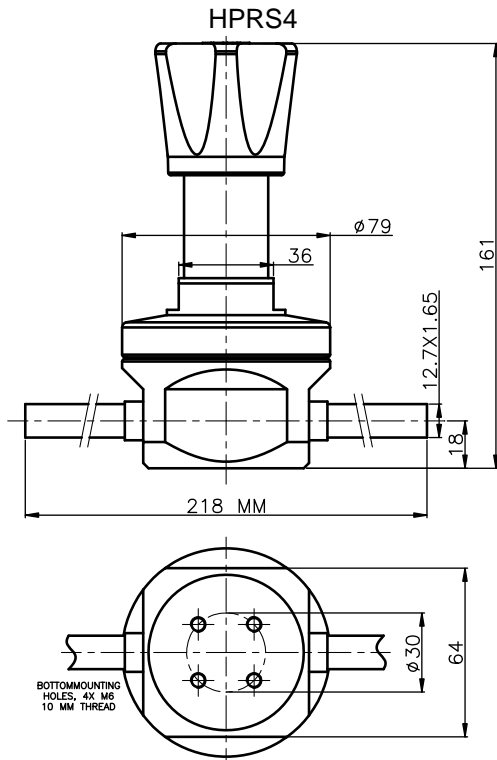
HPRSVF4

MAIN FEATURES

- ss 316L construction
- ss 316L diaphragm
- compliance with FDA/USP class VI
- cleanroom assembly
- cleaned for high purity gases
- metal to metal body/bonnet seal
- orbital weld tube stubs or VCR connections
- internal finish maximal 0,4 µm
- shell design according to EN 12516

CHARACTERISTICS

Inlet pressure	: 35 bar
Outlet range	: 0.3 – 9 bar
Seat diameter	: 6 mm
Cv (Kv):	: 0.45 (0.39)
Materials:	
• Body & Trim	: ss 316L
• Springhousing	: ss 316L
• Diaphragm	: ss 316L
• Seat	: pctfe, peek
Seatleakage:	
• Diaphragm	: 9.0×10^{-5} mbar.L/sec. Helium
• Seat	: 1.8×10^{-9} mbar.L/sec. Helium
Connections	: ½" orbital weld tube stubs
	: ½" vcr female
Weight:	: 2.8 kg
Temperature range	: - 20 °C to + 80 °C



TESTING

All HPRSS regulators are helium leaktested.

ASSEMBLY

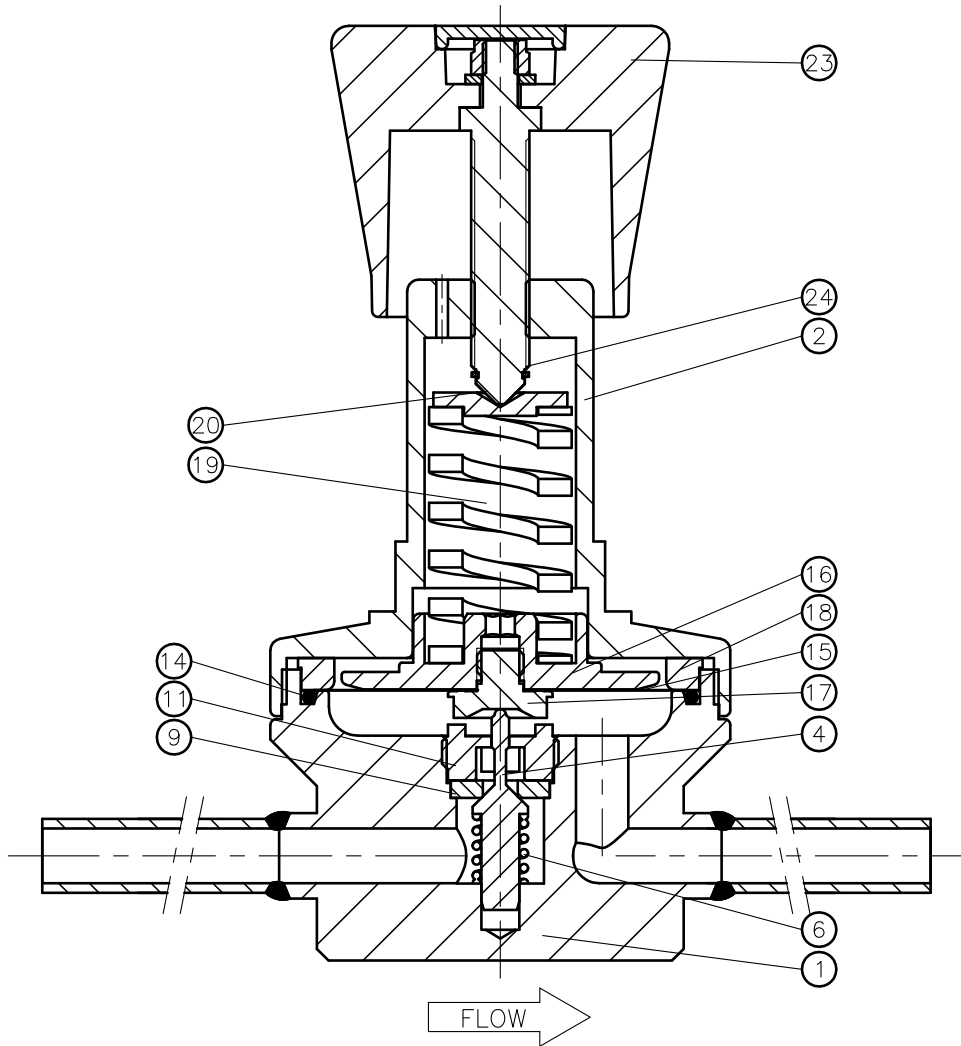
Cleanroom ISO Cl.7, US Cl:10000
Laminar Flowbench ISO Cl.5, US Cl:100

CLEANING

This regulator is ultrasonically cleaned and degreased
Cleaning based on
ASTM-G93 Level C / CGA 4.1 is optional.

⚠ Swagelok regulators are not "Safety Accessories" as defined in the Pressure Equipment Directive 97/23/EC:

⚠ Do not use the regulator as a shut off device.



ORDERING INFORMATION

Example: HPRSS4-02-2-TMK-25

HPRS	S4	- 02	- 2	- T	M	K	- 25
series/inlet	connection	material	outlet range	o-rings	diaphragm	seat	options
HPRS = 35 bar	S4 = ½" weld stubs Ø 12,7 x 1,65 mm VF4 = ½" vcr female	02 = ss316L	1 = 0.3 - 3 bar 2 = 1 - 9 bar	T = ptfe	M = ss316L	K = ptfe* P = peek * max. operating temperature 80°C	25 = 0,25 µm finish

Red text identifies an example ordering number.

Safe Product Selection

When selecting a product, the total system design must be considered to ensure safe, trouble-free performance. Function, material compatibility, adequate ratings, proper installation, operation, and maintenance are the responsibilities of the system designer and user.

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RHPS Series